

# STL18N65M5

Datasheet - preliminary data

### N-channel 650 V, 0.215 Ω typ., 15 A MDmesh<sup>™</sup> V Power MOSFET in a PowerFLAT<sup>™</sup> 5x6 HV package



Figure 1. Internal schematic diagram



# Features

| Order code | V <sub>DS</sub> | R <sub>DS(on)max</sub> . | Ι <sub>D</sub>      |
|------------|-----------------|--------------------------|---------------------|
| STL18N65M5 | 710 V           | 0.240 Ω                  | 15 A <sup>(1)</sup> |

1. The value is rated according to  $\mathsf{R}_{\mathsf{thj}\mathsf{-}\mathsf{case}}$  and limited by package.

- Outstanding R<sub>DS(on)</sub>\*area
- Extremely large avalanche performance
- Gate charge minimized
- Very low intrinsic capacitance
- 100% avalanche tested

### Applications

Switching applications

### Description

This device is an N-channel MDmesh<sup>™</sup> V Power MOSFET based on an innovative proprietary vertical process technology, which is combined with STMicroelectronics' well-known PowerMESH<sup>™</sup> horizontal layout structure. The resulting product has extremely low onresistance, which is unmatched among siliconbased Power MOSFETs, making it especially suitable for applications which require superior power density and outstanding efficiency.

#### Table 1. Device summary

| Order code | Marking | Package           | Packaging     |
|------------|---------|-------------------|---------------|
| STL18N65M5 | 18N65M5 | PowerFLAT™ 5x6 HV | Tape and reel |

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This is preliminary information on a new product now in development or undergoing evaluation. Details are subject to change without notice.

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#### 1

# Electrical ratings

| Symbol                             | Parameter   | Value       | Unit |
|------------------------------------|---|-------------|------|
| V <sub>GS</sub>                    | Gate-source voltage   | ± 25        | V    |
| I <sub>D</sub> <sup>(1)</sup>      | Drain current (continuous) at T <sub>C</sub> = 25 °C  | 15          | A    |
| I <sub>D</sub> <sup>(1)</sup>      | Drain current (continuous) at T <sub>C</sub> = 100 °C   | 6.5         | A    |
| I <sub>DM</sub> <sup>(1),(2)</sup> | Drain current (pulsed)  | 60          | A    |
| P <sub>TOT</sub> <sup>(1)</sup>    | Total dissipation at $T_{C}$ = 25 °C  | 57          | W    |
| I <sub>AR</sub>                    | Avalanche current, repetitive or not-<br>repetitive (pulse width limited by T <sub>j</sub> max)               | 4           | А    |
| E <sub>AS</sub>                    | Single pulse avalanche energy<br>(starting $T_j = 25 \text{ °C}$ , $I_D = I_{AR}$ , $V_{DD} = 50 \text{ V}$ ) | 210         | mJ   |
| dv/dt <sup>(3)</sup>               | Peak diode recovery voltage slope   | 15          | V/ns |
| T <sub>stg</sub>                   | Storage temperature   | - 55 to 150 | °C   |
| Тj                                 | Max. operating junction temperature   | 150         | °C   |

#### Table 2. Absolute maximum ratings

1. The value is rated according to  $\mathsf{R}_{thj\text{-}case}$  and limited by package.

2. Pulse width limited by safe operating area.

3. I\_{SD} ~\leq~ 15 A, di/dt  $~\leq~$  400 A/µs, V\_{Peak}  $\leq$  V\_{(BR)DSS}, V\_{DD} = 400 V.

#### Table 3. Thermal data

| Symbol                              | Parameter                            | Value | Unit |
|-------------------------------------|--------------------------------------|-------|------|
| R <sub>thj-case</sub>               | Thermal resistance junction-case max | 2.2   | °C/W |
| R <sub>thj-pcb</sub> <sup>(1)</sup> | Thermal resistance junction-amb max  | 59    | °C/W |

1. When mounted on 1inch<sup>2</sup> FR-4 board, 2 oz Cu.



### 2 Electrical characteristics

( $T_C = 25$  °C unless otherwise specified)

| Symbol               | Parameter  | Test conditions  | Min. | Тур.  | Max.     | Unit     |
|----------------------|--|--|------|-------|----------|----------|
| V <sub>(BR)DSS</sub> | Drain-source<br>breakdown voltage<br>(V <sub>GS</sub> = 0) | I <sub>D</sub> = 1 mA  | 650  |       |          | V        |
| I <sub>DSS</sub>     | Zero gate voltage<br>drain current (V <sub>GS</sub> = 0)   | V <sub>DS</sub> = 650 V<br>V <sub>DS</sub> = 650 V, T <sub>C</sub> =125 °C |      |       | 1<br>100 | μA<br>μA |
| I <sub>GSS</sub>     | Gate-body leakage<br>current (V <sub>DS</sub> = 0)         | V <sub>GS</sub> = ± 25 V   |      |       | ± 100    | nA       |
| V <sub>GS(th)</sub>  | Gate threshold voltage                                     | $V_{DS} = V_{GS}, I_D = 250 \ \mu A$                                       | 3    | 4     | 5        | V        |
| R <sub>DS(on)</sub>  | Static drain-source on-<br>resistance                      | V <sub>GS</sub> = 10 V, I <sub>D</sub> = 7.5 A                             |      | 0.215 | 0.240    | Ω        |

#### Table 4. On /off states

Table 5. Dynamic

| Symbol                            | Parameter                                   | Test conditions                                   | Min. | Тур. | Max. | Unit |
|-----------------------------------|---|---|------|------|------|------|
| C <sub>iss</sub>                  | Input capacitance                           |   | -    | 1240 | -    | pF   |
| C <sub>oss</sub>                  | Output capacitance                          | V <sub>DS</sub> = 100 V, f = 1 MHz,               | -    | 32   | -    | pF   |
| C <sub>rss</sub>                  | Reverse transfer capacitance                | $V_{GS} = 0$                                      | -    | 3    | -    | pF   |
| C <sub>o(tr)</sub> <sup>(1)</sup> | Equivalent<br>capacitance time<br>related   | V <sub>DS</sub> = 0 to 520 V, V <sub>GS</sub> = 0 | -    | 99   | -    | pF   |
| C <sub>o(er)</sub> <sup>(2)</sup> | Equivalent<br>capacitance energy<br>related | v <sub>DS</sub> = 0 10 320 v, v <sub>GS</sub> = 0 | -    | 30   | -    | pF   |
| R <sub>G</sub>                    | Intrinsic gate<br>resistance                | f = 1 MHz open drain                              | -    | 3    | -    | Ω    |
| Qg                                | Total gate charge                           | V <sub>DD</sub> = 520 V, I <sub>D</sub> = 7.5 A,  | -    | 31   | -    | nC   |
| Q <sub>gs</sub>                   | Gate-source charge                          | V <sub>GS</sub> = 10 V                            | -    | 8    | -    | nC   |
| Q <sub>gd</sub>                   | Gate-drain charge                           | (see Figure 16)                                   | -    | 14   | -    | nC   |

1.  $C_{oss \, eq}$  time related is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ 

2.  $C_{oss eq.}$  energy related is defined as a constant equivalent capacitance giving the same stored energy as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ 



| Symbol              | Parameter           | Test conditions   | Min. | Тур. | Max. | Unit |
|---------------------|---------------------|---|------|------|------|------|
| t <sub>d(on)</sub>  | Turn-on delay time  |   | -    | 36   | -    | ns   |
| t <sub>r</sub>      | Rise time           | $V_{DD} = 400 \text{ V}, \text{ I}_{D} = 9.5 \text{ A},$                      | -    | 7    | -    | ns   |
| t <sub>d(off)</sub> | Turn-off delay time | $R_G = 4.7 \Omega$ , $V_{GS} = 10 V$<br>(see <i>Figure 17</i> and <i>20</i> ) | -    | 9    | -    | ns   |
| t <sub>f</sub>      | Fall time           |   | -    | 11   | -    | ns   |

Table 6. Switching times

Table 7. Source drain diode

| Symbol   | Parameter                     | Test conditions  | Min. | Тур. | Max. | Unit |
|--|-------------------------------|--|------|------|------|------|
| I <sub>SD</sub> <sup>(1)</sup>                   | Source-drain current          |  | -    |      | 15   | А    |
| I <sub>SDM</sub> <sup>(1)</sup> , <sup>(2)</sup> | Source-drain current (pulsed) |  | -    |      | 60   | А    |
| V <sub>SD</sub> <sup>(3)</sup>                   | Forward on voltage            | I <sub>SD</sub> = 15 A, V <sub>GS</sub> = 0  | -    |      | 1.5  | V    |
| t <sub>rr</sub>                                  | Reverse recovery time         |  | -    | 290  |      | ns   |
| Q <sub>rr</sub>                                  | Reverse recovery charge       | I <sub>SD</sub> = 15 A, di/dt = 100 A/μs<br>V <sub>DD</sub> = 60 V (see <i>Figure 17</i> ) | -    | 3.4  |      | μC   |
| I <sub>RRM</sub>                                 | Reverse recovery current      |  | -    | 23.5 |      | А    |
| t <sub>rr</sub>                                  | Reverse recovery time         | I <sub>SD</sub> = 15 A, di/dt = 100 A/µs   | -    | 352  |      | ns   |
| Q <sub>rr</sub>                                  | Reverse recovery charge       | V <sub>DD</sub> = 60 V, T <sub>j</sub> = 150 °C  | -    | 4    |      | μC   |
| I <sub>RRM</sub>                                 | Reverse recovery current      | (see Figure 17)  | -    | 24   |      | A    |

1. The value is rated according to  ${\rm R}_{\rm thj\text{-}case}$  and limited by package.

2. Pulse width limited by safe operating area

3. Pulsed: pulse duration =  $300 \ \mu$ s, duty cycle 1.5%



### 2.1 Electrical characteristics (curves)



Figure 4. Output characteristics







Figure 5. Transfer characteristics











Figure 10. Normalized gate threshold voltage vs. temperature



Figure 12. Drain-source diode forward characteristics



Electrical characteristics



Figure 11. Normalized on-resistance vs. temperature



Figure 13. Normalized  $\mathsf{B}_{\mathsf{VDSS}}$  vs. temperature







# Figure 14. Switching losses vs gate resistance <sup>(1)</sup>

1. Eon including reverse recovery of a SiC diode



8/17



### 3 Test circuits

Figure 15. Switching times test circuit for resistive load



Figure 17. Test circuit for inductive load switching and diode recovery times



Figure 19. Unclamped inductive waveform





#### Figure 16. Gate charge test circuit





Figure 20. Switching time waveform



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# 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK<sup>®</sup> packages, depending on their level of environmental compliance. ECOPACK<sup>®</sup> specifications, grade definitions and product status are available at: *www.st.com*. ECOPACK<sup>®</sup> is an ST trademark.



| Dim. |      | mm   |      |  |  |
|------|------|------|------|--|--|
|      | Min. | Тур. | Max. |  |  |
| A    | 0.80 |      | 1.00 |  |  |
| A1   | 0.02 |      | 0.05 |  |  |
| A2   |      | 0.25 |      |  |  |
| b    | 0.30 |      | 0.50 |  |  |
| D    | 5.00 | 5.20 | 5.40 |  |  |
| E    | 5.95 | 6.15 | 6.35 |  |  |
| D2   | 4.30 | 4.40 | 4.50 |  |  |
| E2   | 3.10 | 3.20 | 3.30 |  |  |
| е    |      | 1.27 |      |  |  |
| L    | 0.50 | 0.55 | 0.60 |  |  |
| К    | 1.90 | 2.00 | 2.10 |  |  |
| aaa  |      | 0.15 |      |  |  |
| bbb  |      | 0.15 |      |  |  |
| ccc  |      | 0.10 |      |  |  |
| eee  |      | 0.10 |      |  |  |

Table 8. PowerFLAT<sup>™</sup> 5x6 HV creepage





Figure 21. PowerFLAT™ 5x6 HV creepage





Figure 22. PowerFLAT<sup>™</sup> 5x6 HV creepage (dimensions are in mm)



# 5 Packaging mechanical data



Figure 23. PowerFLAT™ 5x6 tape









# 6 Revision history

| Date        | Revision | Changes  |
|-------------|----------|--|
| 24-Apr-2013 | 1        | First release  |
| 26-Jun-2013 | 2        | <ul> <li>Modified: Figure 6, 15, 16, 17, 18</li> <li>Minor text changes</li> </ul> |

#### Table 9. Document revision history



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